


<b>Search Notes</b>  	<b>Application/Control No.</b>  10821547	<b>Applicant(s)/Patent Under Reexamination</b>  DIEDRICHSEN, STEFFAN
	<b>Examiner</b>  HAI PHAN	<b>Art Unit</b>  2614

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
381	63, 64, 71.11	11/05/2009	HP
375	350, 343, 232	11/06/2009	HP
375	149-15, 232, 367	11/09/2009	HP
708	250, 271, 314, 322, 323, 420, 422, 425	11/09/2009	HP

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Inventor search	11/05/2009	HP
East search	11/05/2009	HP
PLUS Search	11/06/2009	HP
Consulted primary examiner Young Tse in Class 375 for fields of search	11/06/2009	HP

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/HAI PHAN/ Examiner.Art Unit 2614	
--------------------------------------	--